


U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. APPM/5799		Serial No. 10/084,767	
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT				Applicant Wang, et al.		Confirmation No.: Unknown	
(Use several sheets if necessary)				Filing Date 02/26/2002		Group Unknown 172	
Examiner Unknown							



U.S. Patent Documents							
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
V	A1	4,058,430	11/15/77	Suntola et al.	156	6	11/25/75
	A2	4,389,973	6/28/83	Suntola et al.	156	7	12/11/77
	A3	4,413,022	11/1/83	Suntola et al.	4	23	6/21/77
	A4	4,486,487	12/4/84	Skarp	4	2	4/25/84
	A5	4,767,494	8/30/88	Kobayashi et al.	1	60	9/19/88
	A6	4,806,321	2/21/89	Nishizawa et al.	4	24	7/21/88
	A7	4,813,846	3/21/89	Helms	4	74	4/29/88
	A8	4,829,022	5/9/89	Kobayashi et al.	4	10	12/9/88
	A9	4,834,831	5/30/89	Nishizawa et al.	15	61	9/4/88
	A10	4,838,983	6/13/89	Schumaker et al.	15	61	3/18/88
	A11	4,838,993	6/13/89	Aoki et al.	15	64	12/3/87
	A12	4,840,921	6/20/89	Matsumoto	4	89	6/30/88
	A13	4,845,049	7/4/89	Sunakawa	4	81	3/23/88
	A14	4,859,625	8/22/89	Nishizawa et al.	4	81	11/10/87
	A15	4,859,627	8/22/89	Sunakawa	4	81	7/1/88
	A16	4,861,417	8/29/89	Mochizuki et al.	15	61	3/2/88
	A17	4,876,218	10/24/89	Pessa et al.	4	10	9/1/88
	A18	4,917,556	4/17/90	Stark et al.	4	21	5/1/89
	A19	4,927,670	5/22/90	Erbil	4	25	6/1/88
	A20	4,931,132	6/5/90	Aspnes et al.	15	60	10/1/88
A21	4,951,601	8/28/90	Maydan, et al.	15	7	6/1/89	
A22	4,960,720	10/2/90	Shimbo	43	10	8/1/87	
A23	4,975,252	12/4/90	Nishizawa et al.	42	24	5/1/89	
A24	4,993,357	2/19/91	Scholz	15	7	12/1/89	
A25	5,000,113	3/19/91	Wang et al.	11	7	12/9/86	
A26	5,013,683	5/7/91	Petroff et al.	43	1	1/1/89	

Examiner	Date Considered
	12/3/02

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U.S. Department of Commerce, Patent and Trademark Office				Docket No.		Serial No.	
(PTO Form 1449 modified)				APPM/5799		10/084,767	
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT				Applicant		Confirmation No.:	
				Wang, et al.		Unknown	
(Use several sheets if necessary)				Filing Date		Group	
Examiner Unknown				02/26/2002		Unknown 1762	

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U.S. Patent Documents

*Examiner Initial	Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	
	A27	5,028,565	7/2/91	Chang, et al.	4	1	8/25/91
	A28	5,082,798	1/21/92	Arimoto	4	1	9/27/91
	A29	5,085,885	2/4/92	Foley et al.	4	3	9/10/91
	A30	5,091,320	2/25/92	Aspnes et al.	4	8	6/15/92
	A31	5,130,269	7/14/92	Kitahara et al.	4	1	4/25/92
	A32	5,166,092	11/24/92	Mochizuki et al.	4	1	10/30/92
	A33	5,173,474	12/22/92	Connell, et al.	50	1	3/11/93
	A34	5,186,718	2/16/93	Tepman et al.	29	2	4/15/93
	A35	5,205,077	4/27/93	Wittstock	51	1	8/28/93
	A36	5,225,366	7/6/93	Yoder	437	1	6/22/93
	A37	5,234,561	8/10/93	Randhawa et al.	204	1	8/25/83
	A38	5,246,536	9/21/93	Nishizawa et al.	156	6	3/10/83
	A39	5,250,148	10/5/93	Nishizawa et al.	156	6	11/12/83
	A40	5,254,207	10/19/93	Nishizawa et al.	156	6	11/30/83
	A41	5,256,244	10/26/93	Ackerman	156	6	2/10/93
	A42	5,259,881	11/9/93	Edwards, et al.	118	7	5/17/93
	A43	5,270,247	12/14/93	Sakuma et al.	437	1	7/8/92
	A44	5,278,435	1/11/94	Van Hove et al.	257	1	6/8/92
	A45	5,281,274	1/25/94	Yoder	118	6	2/4/93
	A46	5,286,296	2/15/94	Sato et al.	118	7	1/9/93
	A47	5,290,748	3/1/94	Knuuttila et al.	502	2	7/16/93
	A48	5,294,286	3/15/94	Nishizawa et al.	156	6	1/12/93
	A49	5,296,403	3/22/94	Nishizawa et al.	437	1	10/23/92
	A50	5,300,186	4/5/94	Kitahara et al.	156	6	4/7/93
	A51	5,311,055	5/10/94	Goodman et al.	25	5	11/2/91
	A52	5,316,615	5/31/94	Copel	11	95	3/9/93

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Examiner Unknown							

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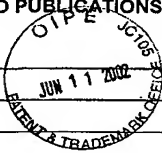
U.S. Patent Documents

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<i>[Signature]</i>	A53	5,316,793	Wallace et al.	427	248.1	7/1/92
	A54	5,330,610	Eres et al.	11	86	5/2/93
	A55	5,336,324	Stall et al.	11	719	12/1/91
	A56	5,338,389	Nishizawa et al.	11	89	4/2/93
	A57	5,348,911	Jurgensen et al.	11	91	4/26/93
	A58	5,374,570	Nasu et al.	43	40	8/19/93
	A59	5,395,791	Cheng et al.	43	10	10/2/93
	A60	5,438,952	Otsuka	1	84	1/31/94
	A61	5,439,876	Graf et al.	5	44	8/16/93
	A62	5,441,703	Jurgensen	4	12	3/29/94
	A63	5,443,033	Nishizawa et al.	1	86	3/11/94
	A64	5,443,647	Aucoin et al.	1	72 ME	7/11/94
	A65	5,455,072	Bension et al.	4	25.7	11/1/92
	A66	5,458,084	Thorne et al.	1	89	12/9/93
	A67	5,469,806	Mochizuki et al.	1	9	8/20/93
	A68	5,480,818	Matsumoto et al.	4	4	2/9/94
	A69	5,483,919	Yokoyama et al.	1	8	8/17/94
	A70	5,484,664	Kitahara et al.	42	6	1/2/94
	A71	5,503,875	Imai et al.	42	25.3	3/17/94
	A72	5,521,126	Okamura et al.	43	5	6/22/94
	A73	5,527,733	Nishizawa et al.	43	10	2/18/94
	A74	5,532,511	Nishizawa et al.	25	7	3/2/95
	A75	5,540,783	Eres et al.	11	86	5/2/94
	A76	5,580,380	Liu, et al.	11	8	1/3/95
	A77	5,601,651	Watabe	11	7	12/1/94
	A78	5,609,689	Kato et al.	11	7	8/3/94

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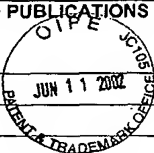
U.S. Patent Documents

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[Signature]	A79	5,616,181	4/1/97	Yamamoto et al.	11	723 ER	11/1/95
	A80	5,637,530	6/10/97	Gaines et al.	11	1	6/1/96
	A81	5,641,984	6/24/97	Aftergut et al.	23	43	8/1/94
	A82	5,644,128	7/1/97	Wollnik et al.	25	25	8/2/94
	A83	5,667,592	9/16/97	Boitnott et al.	11	71	4/1/96
	A84	5,674,786	10/7/97	Turner et al.	43	22	6/5/95
	A85	5,693,139	12/2/97	Nishizawa et al.	11	89	6/15/93
	A86	5,695,564	12/9/97	Imahashi	11	71	8/3/95
	A87	5,705,224	1/6/98	Murota et al.	42	24	1/3/95
	A88	5,707,880	1/13/98	Aftergut et al.	43	3	1/17/97
	A89	5,711,811	1/27/98	Suntola et al.	11	71	11/2/95
	A90	5,730,801	3/24/98	Tepman et al.	11	71	8/2/94
	A91	5,730,802	3/24/98	Ishizumi et al.	11	71	12/2/96
	A92	5,747,113	5/5/98	Tsai	42	25	7/2/96
A93	5,749,974	5/12/98	Habuka et al.	11	72	7/13/95	
A94	5,788,447	8/4/98	Yonemitsu et al.	41	21	8/5/95	
A95	5,788,799	8/4/98	Steger, et al.	15	34	6/1/95	
A96	5,796,116	8/18/98	Nakata et al.	25	66	7/25/95	
A97	5,801,634	9/1/98	Young et al.	34	63	9/8/95	
A98	5,807,792	9/15/98	Ilg et al.	43	75	12/1/96	
A99	5,830,270	11/3/98	McKee et al.	11	10	8/5/95	
A100	5,835,677	11/10/98	Li et al.	35	40	10/3/95	
A101	5,851,849	12/22/98	Comizzoli et al.	43	38	5/22/97	
A102	5,855,675	1/5/99	Doering et al.	11	71	3/3/95	
A103	5,855,680	1/5/99	Soininen et al.	11	71	11/2/95	
A104	5,856,219	1/5/99	Naito et al.	4	24	8/18/97	

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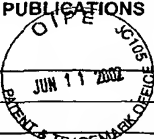


U.S. Patent Documents							
*Examiner Initial	Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	
<i>[Signature]</i>	A105	5,858,102	1/12/99	Tsai	3	719	2/1/98
	A106	5,866,213	2/2/99	Foster et al.	3	573	7/19/97
	A107	5,866,795	2/2/99	Wang et al.	7	1.3	3/17/97
	A108	5,879,459	3/9/99	Gadgil et al.	1	719	8/29/97
	A109	5,882,165	3/16/99	Maydan et al.	4	217	9/10/97
	A110	5,882,413	3/16/99	Beaulieu et al.	1	719	7/11/97
	A111	5,904,565	5/18/99	Nguyen, et al.	4	687	7/17/97
	A112	5,916,365	6/29/99	Sherman	3	92	8/16/96
	A113	5,923,056	7/13/99	Lee et al.	2	192	3/12/98
	A114	5,923,985	7/13/99	Aoki et al.	4	301	1/14/97
	A115	5,925,574	7/20/99	Aoki et al.	4	31	4/10/92
	A116	5,928,389	7/27/99	Jevtic	2	250	10/2/96
	A117	5,942,040	8/24/99	Kim et al.	1	726	8/27/97
A118	5,947,710	9/7/99	Cooper, et al.	4	63	6/16/97	
A119	5,972,430	10/26/99	DiMeo, Jr. et al.	4	255	11/26/97	
A120	6,001,669	12/14/99	Gaines et al.	43	102	7/2/92	
A121	6,015,590	1/18/00	Suntola et al.	42	255	11/23/95	
A122	6,025,627	2/15/00	Forbes et al.	25	321	5/29/98	
A123	6,036,773	3/14/00	Wang et al.	117	97	3/27/97	
A124	6,042,652	3/28/00	Hyun et al.	118	719	9/7/99	
A125	6,043,177	3/28/00	Falconer et al.	502	4	1/2/97	
A126	6,051,286	4/18/00	Zhao et al.	427	576	8/22/97	
A127	6,062,798	5/16/00	Muka	414	416	6/13/96	
A128	6,071,808	6/6/00	Merchant et al.	438	633	6/23/99	
A129	6,084,302	7/4/00	Sandhu	257	75	12/2/95	
A130	6,086,677	7/11/00	Umotoy et al.	118	71	6/16/98	

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U.S. Patent Documents							
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<i>[Signature]</i>	A131	6,110,556	8/29/00	Bang, et al.	42	64	10/1/97
	A132	6,113,977	9/5/00	Soininen et al.	42	84	9/1/97
	A133	6,117,244	9/12/00	Bang, et al.	11	715	3/2/98
	A134	6,124,158	9/26/00	Dautartas et al.	43	216	6/8/99
	A135	6,130,147	10/10/00	Major et al.	43	604	3/18/97
	A136	6,139,700	10/31/00	Kang et al.	20	192	9/30/98
	A137	6,140,237	10/31/00	Chan et al.	43	687	4/19/99
	A138	6,140,238	10/31/00	Kitch	43	687	4/21/99
	A139	6,143,659	11/7/00	Leem	43	688	8/27/98
	A140	6,144,060	11/7/00	Park et al.	25	310	7/31/98
	A141	6,158,446	12/12/00	Mohindra et al.	11	254	9/4/98
	A142	6,174,377	1/16/01	Doering, et al.	11	729	1/4/99
	A143	6,174,809	1/16/01	Kang, et al.	43	682	12/15/98
	A144	6,200,893	3/13/01	Sneh	43	685	3/1/98
	A145	6,203,613	3/20/01	Gates, et al.	11	104	10/19/99
	A146	6,206,967	3/27/01	Mak, et al.	11	660	6/14/00
A147	6,207,302	3/27/01	Suglura, et al.	42	690	3/2/98	
A148	6,248,605	6/19/01	Harkonen, et al.	43	29	6/2/99	
A149	6,270,572	8/7/01	Kim, et al.	11	93	8/9/99	
A150	6,271,148	8/7/01	Kao et al.	43	727	10/19/99	
A151	6,287,965	9/11/01	Kang, et al.	43	648	2/23/00	
A152	6,291,876	9/18/01	Stumborg, et al.	25	612	8/20/98	
A153	6,305,314	10/23/01	Sneh, et al.	11	733 R	12/1/99	
A154	6,306,216	10/23/01	Kim, et al.	11	735	7/12/00	
A155	6,316,098	11/13/01	Yitzchaik, et al.	43	300	3/23/99	
A156	2001/0042799	11/22/01	Kim, et al.	25	633	2/2/01	

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Foreign Patent Documents								
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SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT					Applicant Wang, et al.		Confirmation No.: Unknown	
(Use several sheets if necessary)					Filing Date 02/26/2002		Group 1762	
Examiner Unknown							Unknown	



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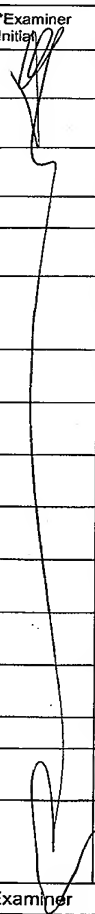


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Examiner	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. APPM/5799	Serial No. 10/084,767
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT		Applicant Wang, et al.	Confirmation No.: Unknown
(Use several sheets if necessary)		Filing Date 02/26/2002	Group Unknown 1762
Examiner Unknown			
OTHER ART			
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.	
W	C1	Hultman, et al., "Review of the thermal and mechanical stability of TiN-based thin films", <i>Zeitschrift Fur Metallkunde</i> , 90(10) (Oct. 1999), pp. 803-813	
	C2	Klaus, et al., "Atomic Layer Deposition of SiO ₂ Using Catalyzed and Uncatalyzed Self-Limiting Surface Reactions", <i>Surface Review & Letters</i> , 6(3&4) (1999), pp. 435-448	
	C3	Yamaguchi, et al., "Atomic-layer chemical-vapor-deposition of silicon dioxide films with extremely low hydrogen content", <i>Appl. Surf. Sci.</i> , Vol. 130-132 (1998), pp. 202-207	
	C4	George, et al., "Surface Chemistry for Atomic Layer Growth", <i>J. Phys. Chem.</i> , Vol. 100 (1996), pp. 13121-131	
	C5	George, et al., "Atomic layer controlled deposition of SiO ₂ and Al ₂ O ₃ using ABAB...binary reaction sequence chemistry", <i>Appl. Surf. Sci.</i> , Vol. 82/83 (1994), pp. 460-467	
	C6	Wise, et al., "Diethyldiethoxysilane as a new precursor for SiO ₂ growth on silicon", <i>Mat. Res. Soc. Symp. Proc.</i> , Vol. 334 (1994), pp. 37-43	
	C7	Niinisto, et al., "Synthesis of oxide thin films and overlayers by atomic layer epitaxy for advanced applications", <i>Mat. Sci. & Eng.</i> , Vol. B41 (1996), pp. 23-29	
	C8	Ritala, et al., "Perfectly conformal TiN and Al ₂ O ₃ films deposited by atomic layer deposition", <i>Chemical Vapor Deposition</i> , Vol. 5(1) (January 1999), pp. 7-9	
	C9	Klaus, et al., "Atomically controlled growth of tungsten and tungsten nitride using sequential surface reactions", <i>Appl. Surf. Sci.</i> , Vol 162-163 (July 1999), pp. 479-491	
	C10	Klaus, et al., "Atomically controlled growth of tungsten and tungsten nitride using sequential surface reactions", <i>Fifth Int'l Symp. On Atomically Controlled Surfaces, Interfaces and Nanostructures</i> (July 6-9, 1999), Aix en Provence, France <i>no page numbers</i>	
	C11	Min, et al., "Atomic layer deposition of TiN thin films by sequential introduction of Ti precursor and NH/sub3", <i>Symp.: Advanced Interconnects and Contact Materials and Processes for Future Integrated Circuits</i> (Apr. 13-16, 1998), pp. 337-342	
	C12	Min, et al., "Metal-Organic Atomic-Layer Deposition of Titanium-Silicon-Nitride Films", <i>Applied Physics Letters</i> , American Inst. Of Physics, Vol 75(11) (Sept. 13, 1999) <i>no page numbers</i>	
	C13	Maertensson, et al., "Atomic Layer Epitaxy of Copper on Tantalum", <i>Chemical Vapor Deposition</i> , 3(1) (Feb. 1, 1997), pp. 45-50	
	C14	Ritala, et al. "Atomic Layer Epitaxy Growth of TiN Thin Films", <i>J. Electrochem. Soc.</i> , 142(8) (Aug. 1995), pp. 2731-737	
	C15	Elers, et al., "NbC15 as a precursor in atomic layer epitaxy", <i>Appl. Surf. Sci.</i> , Vol. 82/83 (1994), pp. 468-474	
Examiner		Date Considered	
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(PTO Form 1449 modified)		APPM/5799	10/084,767
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT		Applicant	Confirmation No.:
		Wang, et al.	Unknown
(Use several sheets if necessary)		Filing Date	Group
Examiner Unknown		02/26/2002	Unknown 1762
OTHER ART			
*Examiner Initial	Including Author, Title, Date, Pertinent Pages, Etc.		
	C16	Lee, "The Preparation of Titanium-Based Thin Film by CVD Using Titanium Chlorides as precursors", <i>Chemical Vapor Deposition</i> , 5(2) (Mar. 1999), pp. 69-73	
	C17	Martensson, et al., "Atomic Layer Epitaxy of Copper, Growth & Selectivity in the Cu (II)-2,2,6,6-Tetramethyl-3, 5-Heptanedion ATE/H2 Process", <i>J. Electrochem. Soc.</i> , 145(8) (Aug. 1998), pp. 2926-2931	
	C18	Min, et al., "Chemical Vapor Deposition of Ti-Si-N Films with Alternating Source Supply", <i>Mat., Res. Soc. Symp. Proc.</i> , Vol. 564 (Apr. 5, 1999), pp. 207-210	
	C19	Bedair, "Atomic layer epitaxy deposition processes", <i>J. Vac. Sci. Technol.</i> 12(1) (Jan/Feb 1994) <i>no page numbers</i>	
	C20	Yamaga, et al., "Atomic layer epitaxy of ZnS by a new gas supplying system in a low-pressure metalorganic vapor phase epitaxy", <i>J. of Crystal Growth</i> 117 (1992), pp. 152-155	
	C21	Ohba, et al., "Thermal Decomposition of Methylhydrazine and Deposition Properties of CVD TiN Thin Films", Conference Proceedings, Advanced Metallization for ULSI Applications in 1993 (1994), pp. 143-149	
	C22	Scheper, et al., "Low-temperature deposition of titanium nitride films from dialkylhydrazine-based precursors", <i>Materials Science in Semiconductor Processing</i> 2 (1999), pp. 149-157	
	C23	Suzuki, et al., "A 0.2- μ m contact filing by 450°C-hydrazine-reduced TiN film with low resistivity", <i>IEDM</i> 92-979, pp. 11.8.1 - 11.8.3 <i>No date available</i>	
	C24	Suzuki, et al., "LPCVD-TiN Using Hydrazine and TiCl ₄ ", VMIC Conference (June 8-9, 1993), pp. 418-423	
	C25	IBM Tech. Disc. Bull. "Knowledge-Based Dynamic Scheduler in Distributed Computer Control, (June 1990), pp. 80-84	
	C26	IBM Tech. Disc. Bull. "Multiprocessor and Multitasking Architecture for Tool Control of the Advanced via Inspection Tools" (May 1992), pp. 190-191	
	C27	McGeachin, S., "Synthesis and properties of some β -diketimines derived from acetylacetone, and their metal complexes", <i>Canadian J. of Chemistry</i> , Vol. 46 (1968), pp.1903-1912	
	C28	Solanki, et al., "Atomic Layer deposition of Copper Seed Layers", <i>Electrochemical and Solid State Letters</i> , 3(10) (2000), pp. 479-480	
C29	NERAC.COM Retro Search: Atomic Layer Deposition of Copper, dated October 11, 2001 <i>no page numbers</i>		
C30	NERAC.COM Retro Search: Atomic Layer Deposition / Epitaxy Aluminum Oxide Plasma, dated October 2, 2001 <i>no page numbers</i>		
C31	NERAC Search abstract of "Atomic Layer deposition of Ta and Ti for Interconnect Diffusion Barriers", by Rossnagel, et al., <i>J. Vac. Sci. & Tech.</i> , 18(4) (July 2000)		
Examiner	Date Considered		

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SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT		Applicant Wang, et al.	Confirmation No.: Unknown
(Use several sheets if necessary)		Filing Date 02/26/2002	Group Unknown 162
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OTHER/ART			
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	C32	Abstracts of articles re atomic layer deposition <i>No date or page numbers</i>	
	C33	Abstracts of search results re atomic layer deposition, search dated January 24, 2002 <i>No page numbers</i>	
	C34	Abstracts of articles re atomic layer deposition and atomic layer nucleation <i>No date or page numbers</i>	
	C35	Abstracts of articles re atomic layer deposition and semiconductors and copper <i>No date or page numbers</i>	
	C36	Abstracts of articles - atomic layer deposition <i>No date or page numbers</i>	
	C37	NERAC Search - Atomic Layer Deposition, search dated October 16, 2001 <i>No page numbers</i>	
	C38	Bader, et al., "Integrated Processing Equipment", Solid State Technology, Cowan Pub., Vol. 33, No. 5 (May 1, 1990), pp. 149-154	
	C39	Choi, et al., "The effect of annealing on resistivity of low pressure chemical vapor deposited titanium diboride", J. Appl. Phys. 69(11) (June 1, 1991), pp. 7853-7861	
	C40	Choi, et al., "Stability of TiB ₂ as a Diffusion Barrier on Silicon", J. Electrochem. Soc. 138(10) (October 1991), pp. 3062-3067	
	C41	"Cluster Tools for Fabrication of Advanced devices" Jap. J. of Applied Physics, Extended Abstracts, 22 nd Conference Solid State Devices and Materials (1990), pp. 849 - 852 XP000178141	
	C42	"Applications of Integrated processing", Solid State Technology, US, Cowan Pub., Vol 37, No. 12 (December 1, 1994), pp. 45-47	
	C43	Kitigawa, et al., "Hydrogen-mediated low temperature epitaxy of Si in plasma-enhanced chemical vapor deposition", Applied Surface Science (2000), pp. 30-34	
	C44	Lee, et al., "Pulsed nucleation for ultra-high aspect ratio tungsten plugfill", Novellus Systems, Inc. (2001), pp. 1-2 (COPY NOT AVAILABLE TO APPLICANT AT THIS TIME)	
Examiner		Date Considered	
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.			

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant Wang, et al.	Confirmation No.: 3478
(Use several sheets if necessary)		Filing Date February 26, 2002	Group 1762
Examiner Unknown			

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A1	6,534,395	03/18/02	Werkhoven, et al.	4	6	03/18/01
	A2	6,511,539	01/28/03	Raaijmakers	4	1	09/18/99
	A3	6,482,740	11/19/02	Soininen, et al.	4	6	05/18/01
	A4	6,482,733	11/19/02	Raaijmakers, et al.	4	6	04/18/01
	A5	6,482,262	11/19/02	Elers, et al.	1	6	10/18/00
	A6	6,475,910	11/05/02	Sneh	4	6	09/18/00
	A7	6,475,276	11/05/02	Elers, et al.	1	6	10/18/00
	A8	6,468,924	10/22/02	Lee, et al.	4	7	05/18/01
	A9	6,451,695	09/17/02	Sneh	4	6	12/18/00
	A10	6,447,933	09/10/02	Wang, et al.	4	6	04/18/01
	A11	6,428,859	08/06/02	Chiang, et al.	4	4	03/18/01
	A12	6,423,619	07/23/02	Grant, et al.	4	5	11/18/01
	A13	6,420,189	07/16/02	Lopatin	43	2	04/18/01

Foreign Patent Documents

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OTHER ART

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	C1	Yang, et al. "Atomic Layer Deposition of Tungsten Film from WF ₆ /B ₂ H ₆ : Nucleation Layer for Advanced Semiconductor Device," Conference Proceedings ULSI XVII (2002) Materials Research Society no page numbers
	C2	
	C3	

Examiner

Date Considered

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. AMAT/5799/TSG/ALD /BG		Serial No. 10/084,767	
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GROUP 1700

U.S. Patent Documents							
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	A1	6,416,822	07/09/02	Chiang, et al.	407	501	03/19/01
	A2	6,399,491	06/04/02	Jeon, et al.	408	600	04/06/01
	A3	6,391,803	05/21/02	Kim, et al.	408	700	06/20/01
	A4	6,391,785	05/21/02	Satta, et al.	408	700	08/23/00
	A5	6,372,598	04/16/02	Kang, et al.	408	300	06/16/99
	A6	6,369,430	04/09/02	Adetutu, et al.	407	300	04/02/01
	A7	6,368,954	04/09/02	Lopatin, et al.	408	600	07/28/00
	A8	6,358,829	03/19/02	Yoon, et al.	408	500	09/16/99
	A9	6,355,561	03/12/02	Sandhu, et al.	408	600	11/21/00
	A10	6,342,277	01/29/02	Sherman	407	500	04/14/99
	A11	6,333,260	12/25/01	Kwon	407	600	06/24/99
	A12	6,284,646	09/04/01	Leem	407	600	08/19/98
	A13	6,207,487	03/27/01	Kim, et al.	407	238	10/12/99

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	B3	1,167,569	01/02/02	EP	C02C	16/00	YES <input type="checkbox"/> NO <input type="checkbox"/>

OTHER ART	
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Examiner	Date Considered

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U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. AMAT/5799/TSG/ALD /BG		Serial No. 10/084,767	
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(Use several sheets if necessary)				Filing Date February 26, 2002		Group 1762	
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	A2	2003/0082296	05/01/03	Elers, et al.	47	90	09/11/02
	A3	2003/0072975	04/17/03	Shero, et al.	48	70	09/26/02
	A4	2003/0049942	03/13/03	Haukka, et al.	48	70	08/22/02
	A5	2003/0032281	02/13/03	Werkhoven, et al.	48	64	09/23/02
	A6	2003/0031807	02/13/03	Elers, et al.	47	50	09/17/02
	A7	2003/0013320	01/16/03	Kim, et al.	48	70	05/31/01
	A8	2002/0197402	12/26/02	Chiang, et al.	47	2539	08/01/02
	A9	2002/0187631	12/12/02	Kim, et al.	48	60	12/01/01
	A10	2002/0187256	12/12/02	Elers, et al.	47	90	07/31/02
	A11	2002/0182320	12/05/02	Leskela, et al.	47	25	03/15/02
	A12	2002/0164423	11/07/02	Chiang, et al.	47	2528	05/13/02
	A13	2002/0164421	11/07/02	Chiang, et al.	47	2521	05/13/02
	A14	2002/0162506	11/07/02	Sneh, et al.	48	70	06/18/02
	A15	2002/0155722	10/24/02	Satta, et al.	48	70	04/15/02
	A16	2002/0146511	10/10/02	Chiang, et al.	47	2521	10/24/01
	A17	2002/0144657	10/10/02	Chiang, et al.	48	70	10/03/01
	A18	2002/0144655	10/10/02	Chiang, et al.	48	70	10/24/01
	A19	2002/0121697	09/05/02	Marsh	28	70	04/30/02
	A20	2002/0117399	08/29/02	Chen, et al.	28	10	02/23/01
	A21	2002/0109168	08/15/02	Kim, et al.	28	20	01/30/02
	A22	2002/0106846	08/08/02	Seutter, et al.	48	20	02/02/01
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	A24	2002/0104481	08/08/02	Chiang, et al.	48	70	03/19/01
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Examiner [Signature]					Date Considered [Signature]		

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	A2	2002/0076837	06/20/02	Hujanen, et al.	43	3	11/20/01
	A3	2002/0076508	06/20/02	Chiang, et al.	43	56	12/10/01
	A4	2002/0076507	06/20/02	Chiang, et al.	43	56	10/20/01
	A5	2002/0076481	06/20/02	Chiang, et al.	43	8	10/20/01
	A6	2002/0073924	06/20/02	Chiang, et al.	1	7	10/20/01
	A7	2002/0068458	06/06/02	Chiang, et al.	43	6	11/20/01
	A8	2002/0061612	05/23/02	Sandhu, et al.	43	1	01/10/02
	A9	2002/0055235	05/09/02	Agarwal, et al.	43	4	10/20/01
	A10	2002/0052097	05/02/02	Park	43	5	05/00/01
	A11	2002/0048880	04/25/02	Lee	43	3	08/00/01
	A12	2002/0047151	04/25/02	Kim, et al.	25	1	07/00/01
	A13	2002/0037630	03/28/02	Agarwal, et al.	43	0	10/20/01
	A14	2002/0031618	03/14/02	Sherman	42	9	10/20/01
	A15	2002/0019121	02/14/02	Pyo	43	8	06/00/01
	A16	2002/0016084	02/07/02	Todd	43	1	04/00/01
	A17	2002/0007790	01/24/02	Park	1	5	05/00/01
	A18	2002/0004293	01/10/02	Soininen, et al.	43	0	05/00/01
	A19	2002/0000598	01/03/02	Kang, et al.	27	3	07/00/01
	A20	2001/0054769	12/27/01	Raijmakers, et al.	27	7	04/00/01
	A21	2001/0054730	12/27/01	Kim, et al.	27	3	05/00/01
	A22	2001/0029094	10/11/01	Mee-Young, et al.	43	5	09/00/99
	A23	2001/0028924	10/11/01	Sherman	42	28	05/00/01
	A24	2001/0024387	09/27/01	Raijmakers, et al.	27	2	02/00/01
	A25	2001/0009695	07/26/01	Saaniila, et al.	43	39	01/00/01
	A26	2001/0002280	05/31/01	Sneh	42	28	12/00/00
Examiner				Date Considered			

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